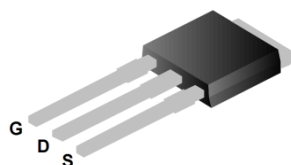
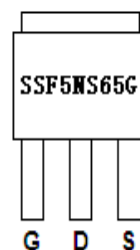
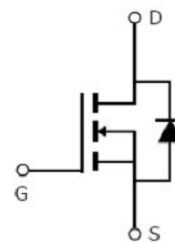


**Main Product Characteristics:**

$V_{DSS}$	650V
$R_{DS(on)}$	1.0 $\Omega$ (typ.)
$I_D$	5A ①


**TO-251**

**Marking and pin Assignment**

**Schematic diagram**
**Features and Benefits:**
**Features:**

- High dv/dt and avalanche capabilities
- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance


**Description:**

The SSF5NS65G series MOSFETs is a new technology, which combines an innovative super junction technology and advance process. This new technology achieves low Rdson, energy saving, high reliability and uniformity, superior power density and space saving.

**Absolute max Rating:**

Symbol	Parameter	Max.	Units
$I_D$ @ TC = 25°C	Continuous Drain Current, $V_{GS}$ @ 10V	5 ①	A
$I_D$ @ TC = 100°C	Continuous Drain Current, $V_{GS}$ @ 10V	3.1 ①	
$I_{DM}$	Pulsed Drain Current ②	15	
$P_D$ @TC = 25°C	Power Dissipation ③	50	W
	Linear Derating Factor	0.4	W/°C
$V_{DS}$	Drain-Source Voltage	650	V
$V_{GS}$	Gate-to-Source Voltage	± 30	V
$E_{AS}$	Single Pulse Avalanche Energy @ L=22.4mH	54	mJ
$I_{AR}$	Avalanche Current @ L=22.4mH	2.2	A
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	°C

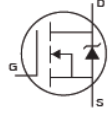
## Thermal Resistance

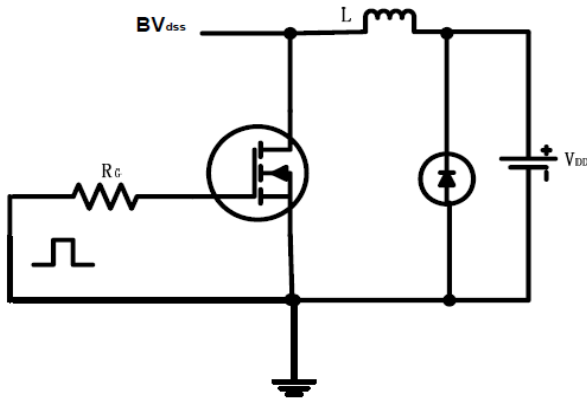
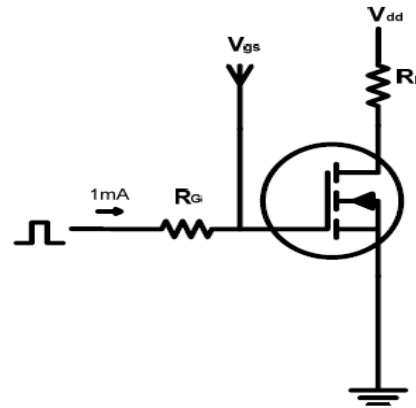
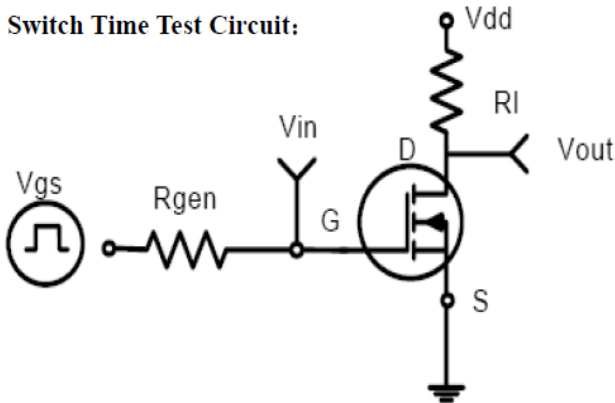
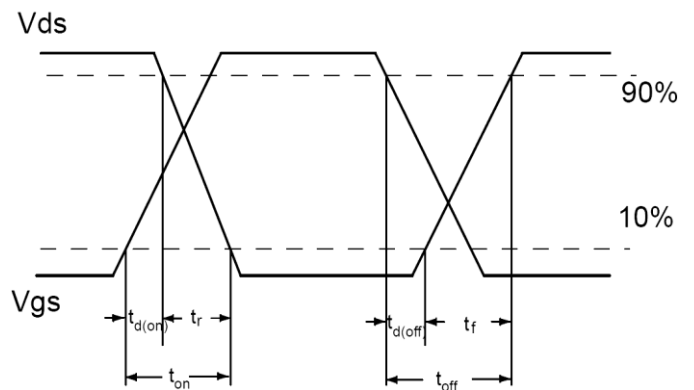
Symbol	Characterizes	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-case ③	—	2.5	$^{\circ}\text{C}/\text{W}$
$R_{\theta JA}$	Junction-to-ambient ( $t \leq 10\text{s}$ ) ④	—	75	$^{\circ}\text{C}/\text{W}$

## Electrical Characterizes @ $T_A=25^{\circ}\text{C}$ unless otherwise specified

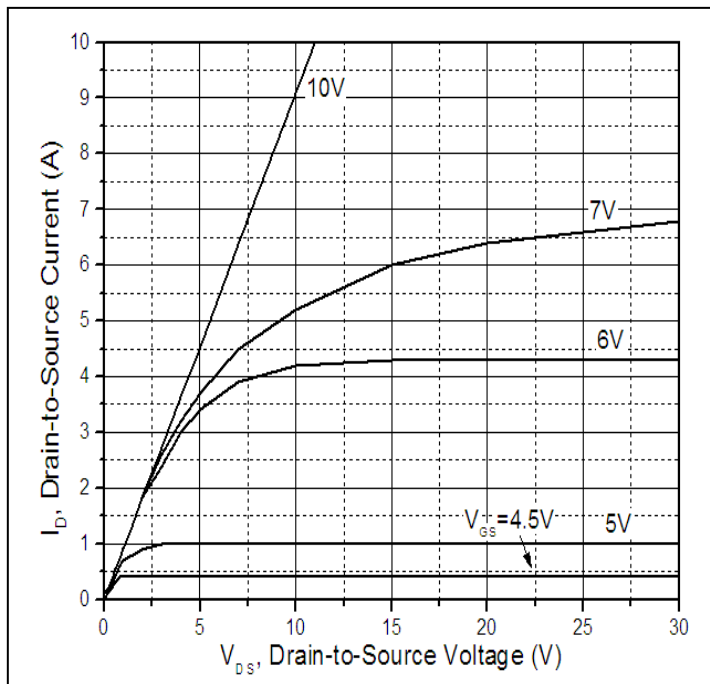
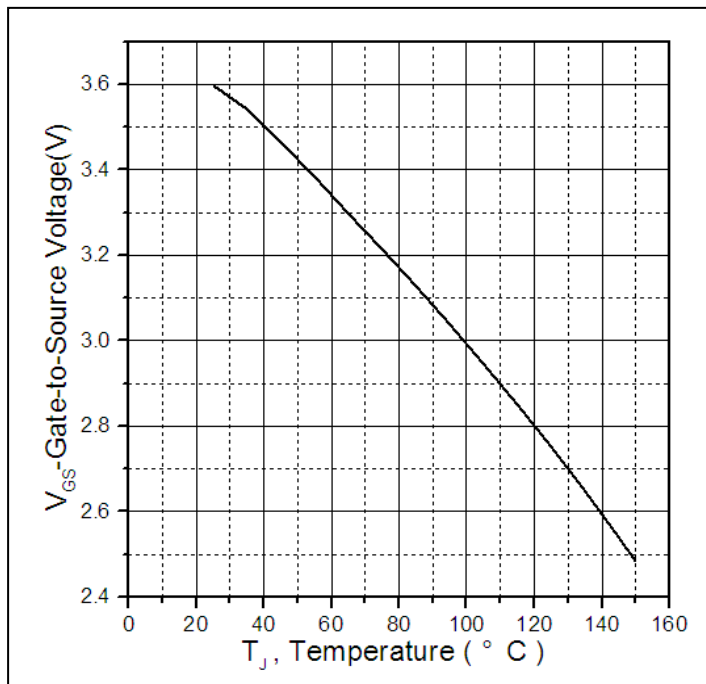
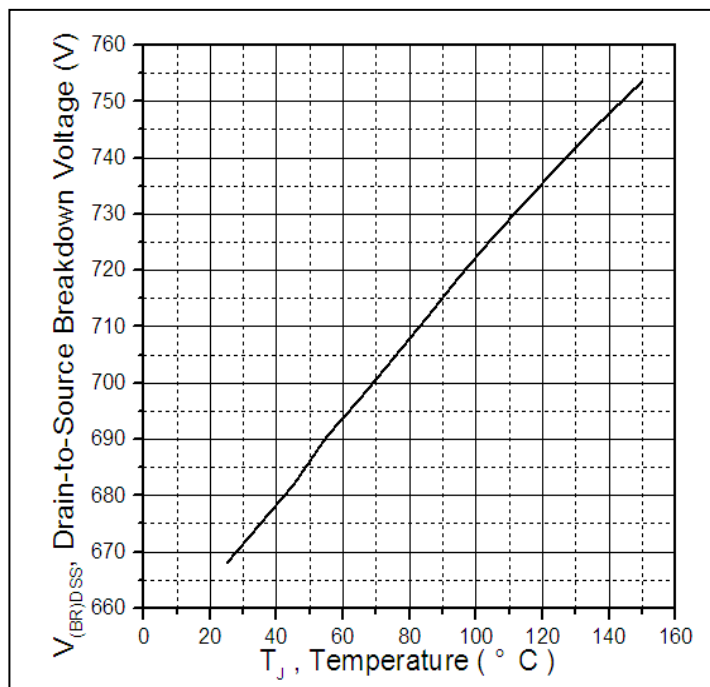
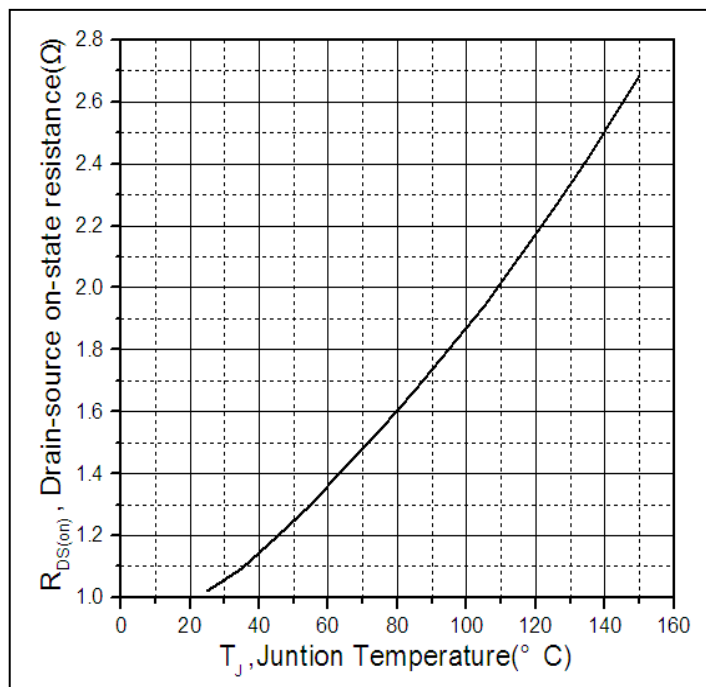
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	650	—	—	V	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$
$R_{DS(on)}$	Static Drain-to-Source on-resistance	—	1.0	1.2	$\Omega$	$V_{GS}=10\text{V}, I_D = 1\text{A}$
		—	2.2	—		$T_J = 125^{\circ}\text{C}$
$V_{GS(th)}$	Gate threshold voltage	2	—	4	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
		—	2.7	—		$T_J = 125^{\circ}\text{C}$
$I_{DSS}$	Drain-to-Source leakage current	—	—	1	$\mu\text{A}$	$V_{DS} = 650\text{V}, V_{GS} = 0\text{V}$
		—	—	50		$T_J = 125^{\circ}\text{C}$
$I_{GSS}$	Gate-to-Source forward leakage	—	—	100	nA	$V_{GS} = 30\text{V}$
		—	—	-100		$V_{GS} = -30\text{V}$
$Q_g$	Total gate charge	—	8.3	—	nC	$I_D = 4\text{A},$ $V_{DS}=100\text{V},$ $V_{GS} = 10\text{V}$
$Q_{gs}$	Gate-to-Source charge	—	2.3	—		
$Q_{gd}$	Gate-to-Drain("Miller") charge	—	2.6	—		
$t_{d(on)}$	Turn-on delay time	—	9.9	—	ns	$V_{GS}=10\text{V}, V_{DS} = 380\text{V},$ $R_{GEN}=18\Omega, I_D = 4.5\text{A}$
$t_r$	Rise time	—	18.4	—		
$t_{d(off)}$	Turn-Off delay time	—	18.1	—		
$t_f$	Fall time	—	15.3	—		
$C_{iss}$	Input capacitance	—	267	—	pF	$V_{GS} = 0\text{V}$
$C_{oss}$	Output capacitance	—	220	—		$V_{DS} = 25\text{V}$
$C_{rss}$	Reverse transfer capacitance	—	4.76	—		$f = 1\text{MHz}$

## Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	5 ①	A	MOSFET symbol showing the integral reverse p-n junction diode. 
$I_{SM}$	Pulsed Source Current (Body Diode)	—	—	15	A	
$V_{SD}$	Diode Forward Voltage	—	0.85	1.2	V	$I_S=2.8\text{A}, V_{GS}=0\text{V}$
$t_{rr}$	Reverse Recovery Time	—	284	—	nS	$T_J = 25^{\circ}\text{C}, I_F = I_S,$
$Q_{rr}$	Reverse Recovery Charge	—	1395	—	nC	$di/dt = 100\text{A}/\mu\text{s}$

**Test circuits and Waveforms**
**EAS test circuits:**

**Gate charge test circuit:**

**Switch Time Test Circuit:**

**Switch Waveforms:**

**Notes:**

- ① Calculated continuous current based on maximum allowable junction temperature.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$

**Typical electrical and thermal characteristics**

**Figure 1: Typical Output Characteristics**

**Figure 2. Gate to source cut-off voltage**

**Figure 3. Drain-to-Source Breakdown Voltage Vs. Case Temperature**

**Figure 4: Normalized On-Resistance Vs. Case Temperature**

Typical electrical and thermal characteristics

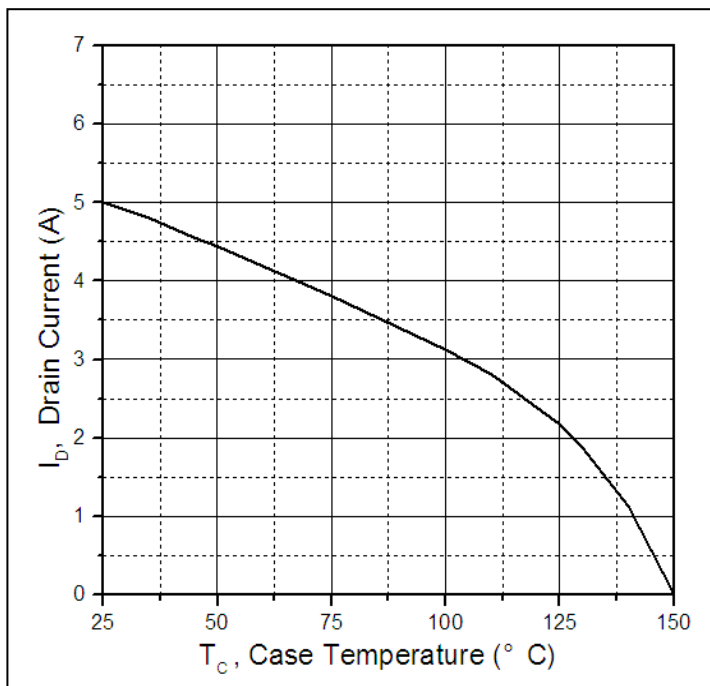


Figure 5. Maximum Drain Current Vs. Case Temperature

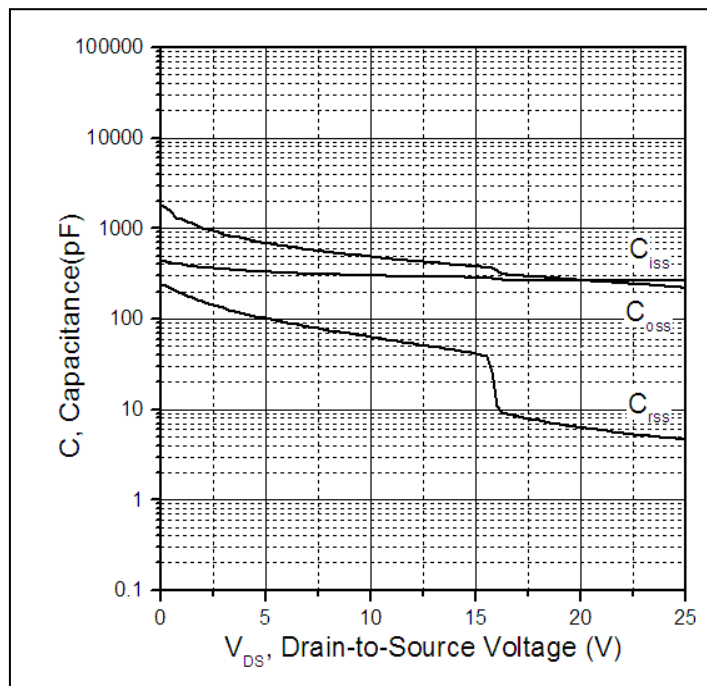


Figure 6. Typical Capacitance Vs. Drain-to-Source Voltage

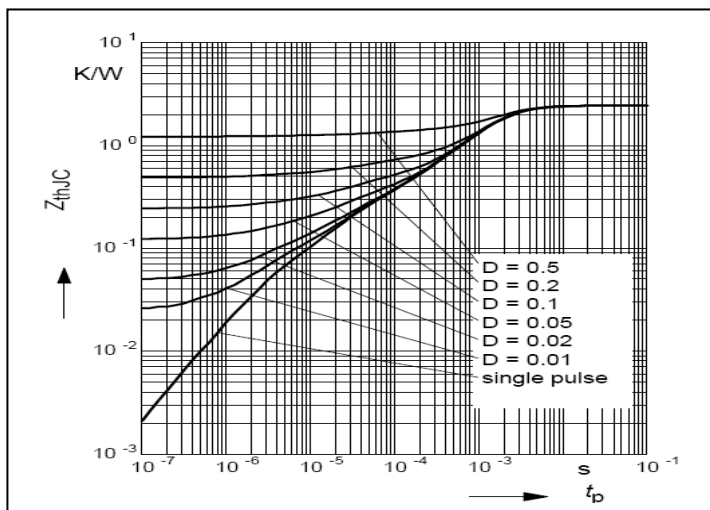
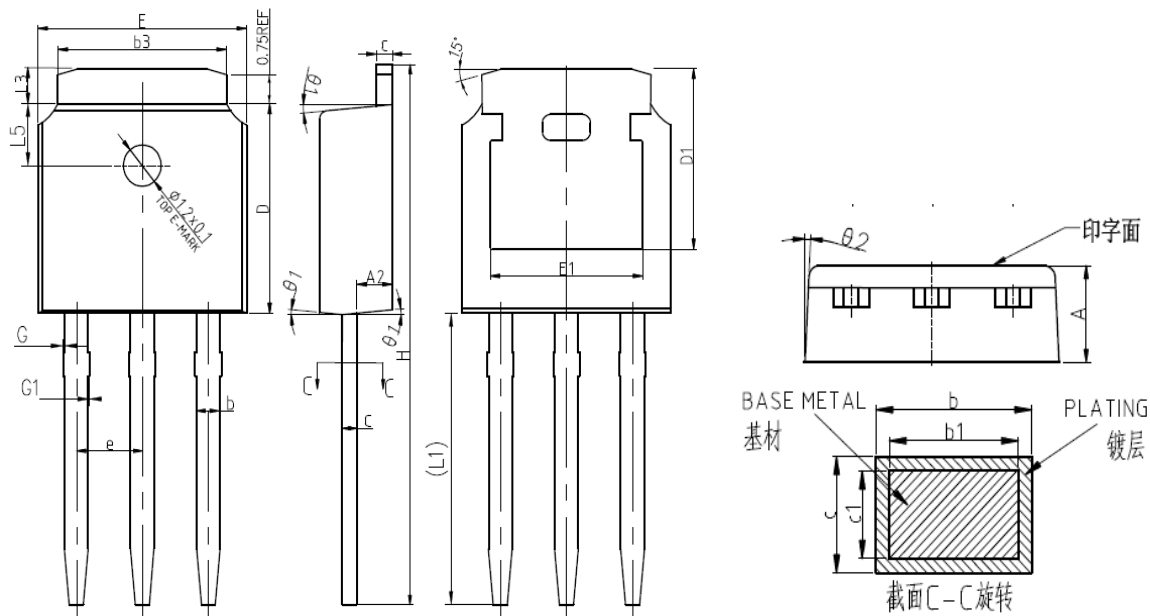


Figure 7. Maximum Effective Transient Thermal Impedance Junction-to-Case

**Mechanical Data:**
**TO-251 PACKAGE OUTLINE DIMENSION**


Symbol	Dimension In Millimeters			Dimension In Inches		
	Min	Nom	Max	Min	Nom	Max
A	2.200	2.300	2.380	0.087	0.091	0.094
A2	0.970	1.070	1.170	0.038	0.042	0.046
b	0.720	0.780	0.850	0.028	0.031	0.033
b1	0.710	0.760	0.810	0.028	0.030	0.032
b3	5.230	5.330	5.460	0.206	0.210	0.215
c	0.470	0.530	0.580	0.019	0.021	0.023
c1	0.460	0.510	0.560	0.018	0.020	0.022
D	6.000	6.100	6.200	0.236	0.240	0.244
D1	5.300REF			0.209REF		
E	6.500	6.600	6.700	0.256	0.260	0.264
E1	4.700	4.830	4.920	0.185	0.190	0.194
e	2.286BSC			0.090BSC		
H	16.100	16.400	16.600	0.634	0.646	0.654
L1	9.200	9.400	9.600	0.362	0.370	0.378
L3	0.900	1.020	1.250	0.035	0.040	0.049
L5	1.700	1.800	1.900	0.067	0.071	0.075
$\theta 1$	5°	7°	9°	5°	7°	9°
$\theta 2$	5°	7°	9°	5°	7°	9°
G	0.000		0.076	0.000	0.000	0.003
G1	0.000		0.076	0.000	0.000	0.003

**Ordering and Marking Information**
**Device Marking: SSF5NS65G**

**Package (Available)**  
**TO-251(IPAK)**  
**Operating Temperature Range**  
**C : -55 to 150 °C**

**Devices per Unit**

Package Type	Units/Tube	Tubes/Inner Box	Units/Inner Box	Inner Boxes/Carton Box	Units/Carton Box
TO-251	80	60	4800	5	24000

**Reliability Test Program**

Test Item	Conditions	Duration	Sample Size
High Temperature Reverse Bias(HTRB)	$T_j=125^{\circ}\text{C}$ to $150^{\circ}\text{C}$ @ 80% of Max $V_{DSS}/V_{CES}/V_R$	168 hours 500 hours 1000 hours	3 lots x 77 devices
High Temperature Gate Bias(HTGB)	$T_j=150^{\circ}\text{C}$ @ 100% of Max $V_{GSS}$	168 hours 500 hours 1000 hours	3 lots x 77 devices

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